

**Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)**

Contribution ID : 10

Type : **not specified**

**Poster presentations: short oral presentation by
each participant**

Tuesday, 27 September 2016 14:00 (2:00)

Content

Summary

Presenter(s) : ALL PARTICIPANTS AND FACULTY

Session Classification : DAY 2